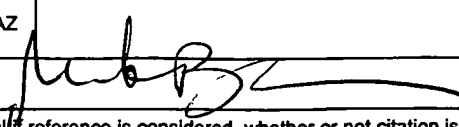


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 286321US0PCT		SERIAL NO. 68582 New U.S. PCT Application Based on PCT/JP04/11856	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Takashi KIKUKAWA, et al.			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
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	AG						
	AH						
	AI						
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	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	2004-220687	08/05/04	JP			NO
	AP	2004-39177	02/05/04	JP			NO
	AQ	2004-087073	03/18/04	JP (with English abstract)			NO
	AR						
	AS						
	AT						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AU	FUJI Hiroshi et al., "A Near-Field Recording and Readout Technology Using a Metallic Probe in an Optical Disk", Japanese Journal of Applied Physics, Vol. 39, Part 1, No. 2B, Pages 980 - 981, 2000.					
	AV	KIKUKAWA T. et al., "Rigid bubble pit formation and huge signal enhancement in super-resolution near-field structure disk with platinum-oxide layer", Applied Physics Letters, Vol. 81, No. 25, Pages 4697 - 4699, 2002.					
	AW	OKIKUKAWA T. et al., "Basic properties of Super-RENS disc with platinum oxide as a mask layer TDK", Vol. 63, page 1005, 2002.					
	AX	KIM Jooho et al., "Super-resolution by elliptical bubble formation with PtO ₂ and AgInSbTe layers", Applied Physics Letters, Vol. 83, No. 9, Pages 1701-1703, 2003.					
	AY	KIM Jooho et al., "Signal Characteristics of Super-RENS Disk at Blue Laser System", Technical Digest of International Symposium on Optical Memory, Pages 264 - 265, 2003.					
	AZ	KIM Jooho et al., "Random Pattern Signal Characteristics of Super-RENS Disk at Blue Laser System", Technical Digest of Optical Data Storage Topical Meeting, Pages 273 - 275, 2004.				<input type="checkbox"/> Additional References sheet(s) attached	
Examiner				Date Considered 1/4/08			
*Examiner: initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 286321US0PCT		SERIAL NO. 10/568,582	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Takashi KIKUKAWA, et al.			
				FILING DATE February 17, 2006		GROUP 2884	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	CN 1672202 A	9-21-2005	China (with English Abstract)		X	
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner 					Date Considered 1/4/07		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



Docket No.: 286321US0PCT

Serial No.: 10/568,582

Inventor: Takashi KIKUKAWA, et al.

LIST OF RELATED CASES CITED BY
APPLICANT UNDER 37 CFR 1.56

Filing Date: February 17, 2006

Group:

LIST OF RELATED CASES

Examiner <u>Initial</u>	<u>Docket No.</u>	Serial or <u>Patent</u> <u>Number</u>	Filing or <u>Issue Date</u>	Patent App. <u>Publication</u> <u>No.</u>	Inventor or <u>Applicant</u>
	286321US0PCT*	10/568,582	02/17/06		KIKUKAWA, et al.
	286323US0PCT	10/568,586	02/17/06		KIKUKAWA, et al.
	287042US2PCT	10/570,659	03/06/06		KIKUKAWA, et al.
	285143US0	11/337,611	01/24/06		KOBAYASHI, et al.
	284873US2PCT	10/565,679	01/24/06		FUKUZAWA, et al.

Examiner

Date Considered

1/4/07

*Present Application; listed for information
NFO/sbs/kch